Abstracts

Analysis of microstrip lines in multilayer structures of arbitrarily varying thickness

A. Dreher and A. Ioffe. "Analysis of microstrip lines in multilayer structures of arbitrarily varying thickness." 2000 Microwave and Guided Wave Letters 10.2 (Feb. 2000 [MGWL]): 52-54.

A general approach to the full-wave analysis of microstrip lines in multilayer dielectrics of arbitrarily varying thickness is developed. It is based on the discrete mode matching technique (DMM) and uses a full-wave equivalent circuit for the stratified structure, which is simple to apply in a numerical procedure, As an example, the propagation constant of a microstrip line in the interface of two dielectrics as a function of different shape characteristics is computed.

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